

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner George A. Goudreau	Art Unit 1763	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0235262	11-2004	Lee et al.	438/411
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	FR 2,799,307	04-2001	France	Bois et. al.	-----
	O	WO 200,057,480	09-2000	WO	Jurczak et. al.	-----
	P					
	Q					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Silicon On Nothing (SON)-Fabrication, Material and Devices"; Proceedings-Electrochemical Society volume 2001-3; (2001'); pp. 391-402; Skotnicki
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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